

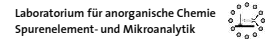
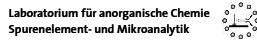
# Characterization of Catalysts and Surfaces

## Elemental Analysis (ICP, AAS etc.)

Fall Semester 2016  
 Bodo Hattendorf  
 HCI G105  
 bodo@inorg.chem.ethz.ch

## Outline

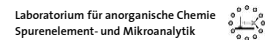
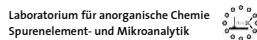
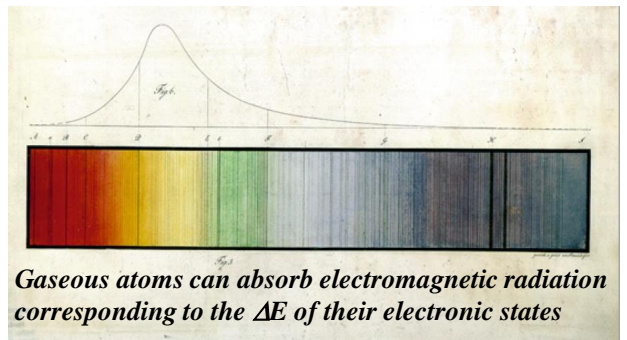
- Instrumental Methods for Determination of the Elements
  - Atomic Absorption Spectrometry - **AAS**
  - Inductively Coupled Plasma Optical Emission Spectrometry - **ICPOES**
  - Inductively Coupled Plasma Mass Spectrometry - **ICPMS**
- Sample Preparation Techniques
- Considerations for Quantitative Analysis



## Common Aspects

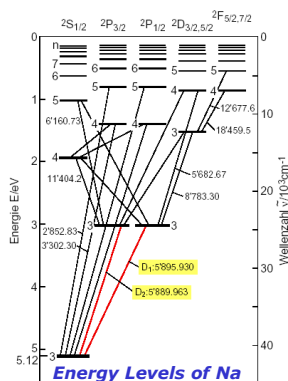
- Solution-based Techniques
  - Usually aqueous
  - Usually acidified (HNO<sub>3</sub>, HCl; 1-10 Vol.%)
  - Digestion of solids required
- Calibration required
  - External standards / Standard Addition
  - Matrix-matching may be required
  - Internal standards (when applicable)

## Atomic Absorption Spectrometry



## Atomic Absorption

- Photons of sufficient energy excite electrons to higher levels
- Excitation is most likely for "resonant" photon, i.e.:  $h\nu = \Delta E$



## Atomic Absorption Spectrometry

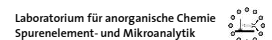
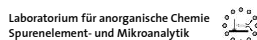
The magnitude of this absorption is given by **Lambert-Beer's law**:

$$I = I_0 e^{-\epsilon_\lambda Lc}$$

$$E = \lg \frac{I_0}{I} = \epsilon_\lambda Lc$$

- I: Intensity registered in presence of an absorber (analyte atom)
- I<sub>0</sub>: Intensity registered in absence of an absorber (analyte atom)
- ε<sub>λ</sub>: Absorption coefficient
- λ: Wavelength registered
- L: Observation path length
- c: Concentration of the analyte
- E: Extinction (evaluated signal)

AAS (and ICPOES) operate in the UV-VIS range, ≈ 200 – 800 nm



## Atomic Absorption Spectrometry

So what do we need for an AAS Experiment?

- 1) **Gaseous Atoms** → **Flame or Furnace**
- 2) **Photon source** → **line- or continuous**  
(ideally resonant  $h\nu$ ) (HCL, EDL or arc)
- 3) **Optical Spectrometer**  
(Monochromator, Detector)

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## Atomic Absorption Spectrometry

### Flame Atomizer

Oxidants: Air,  $N_2O$ ,  $O_2$   
Fuel: Acetylene,  $H_2$ ,  $CH_4$ ,  $C_3H_8$

Oxidant	Fuel	T, °C
Air	$CH_4$	1875
Air	$C_2H_2$	1930
Air	$N_2$	2045
Air	Acetylene	2300
$N_2O$	Acetylene	2750
$O_2$	$H_2$	2680
$O_2$	Acetylene	2500



### Furnace Atomizer

Electrically heated up to 2700 °C



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## Atomic Absorption Spectrometry

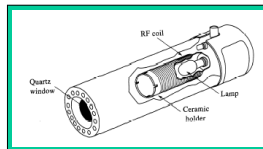
### Line Sources

Element-specific emission spectra

Hollow Cathode Lamp  
HCL



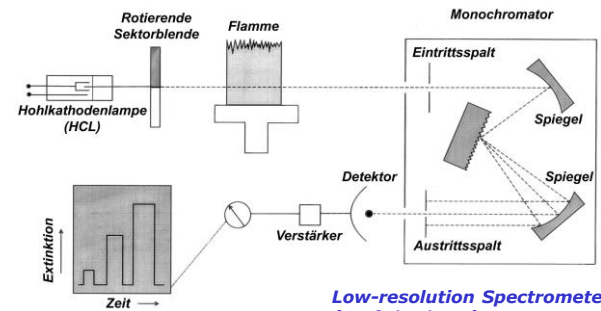
Electrodeless Discharge Lamp  
EDL



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## Atomic Absorption Spectrometry



**Low-resolution Spectrometer**  
( $\Delta\lambda$ : 0.1 - 1 nm)

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## Atomic Absorption Spectrometry

### Spectral Interferences

Absorption (atomic or molecular)  
Scattered radiation  
→ Background correction required:  
 $D_2$ -Lamp, Zeeman-effect

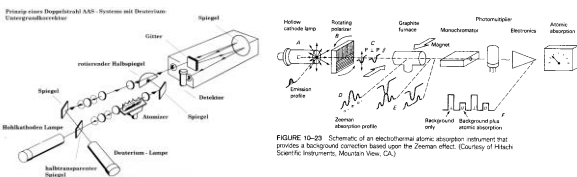


FIGURE 10-23 Schematic of an electrothermal atomic-absorption interferometer that provides a background correction based upon the Zeeman effect. (Courtesy of Hitachi Scientific Instruments, Mountain View, CA)

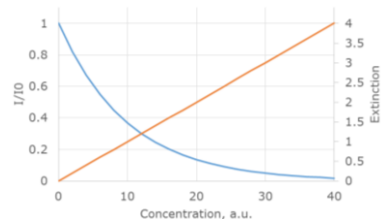
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## Atomic Absorption Spectrometry

### Limited dynamic range

Small change of  $I/I_0$  when the extinction exceeds  $\approx 1$   
→ Higher uncertainty of the concentration.



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## Atomic Absorption Spectrometry

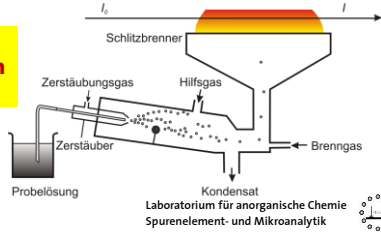
### Flame AAS Principle

Sample is nebulized and aerosol transferred to burner.

Optimization:

- Fuel/Oxidant gas flow rates
- Observation height

**Temperature**  
**Particle formation**  
**Residence time**



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## Atomic Absorption Spectrometry

### Furnace AAS



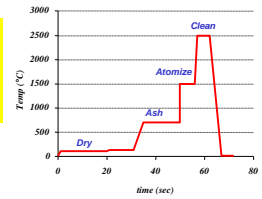
Sample is pipetted into furnace (addition of modifier) and T-program started.

Optimization:

- T-program: Drying, Ashing, Atomization, Cleaning
- Modifier type and amount

**Separation of Analyte from sample matrix and Solvent. Efficient vaporization.**

**Common Modifiers:**  
 $Mg(NO_3)_2$ ,  $Pd(NO_3)_2$ ,  $NH_4H_2PO_4$



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## Atomic Absorption Spectrometry

### Characteristics

	Flame AAS	Furnace AAS
Sample Volume	mL	$\mu$ L
Analysis Time	seconds	minutes
Calibration <sup>1</sup>	Ext./Std.Add.	Std.Add.
Limits of Detection <sup>2</sup>	0.1 – 1000 $\mu$ g/L	0.001 -10 $\mu$ g/L
Repeatability <sup>3</sup>	1-5%	1-5%

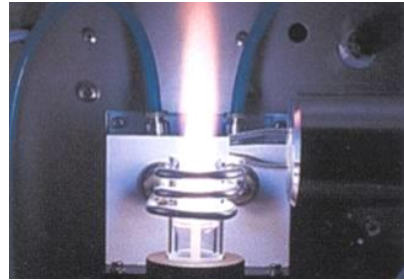
- Ext: External Calibration, Std.Add.: Standard Addition
- Depends on Element, Matrix, Analysis Time
- For Concentrations > 100xLOD

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## ICP-Optical Emission Spectrometry

ICP: Inductively Coupled Plasma  
An Rf-powered electrodeless gas (Ar) discharge, reaching Temperatures of 10000K



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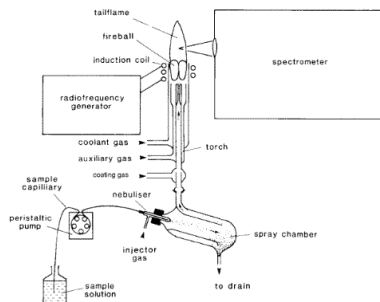
## ICP-Optical Emission Spectrometry

### Setup

Nebulizer Gas:  $\approx$  1 L/min Ar  
Auxiliary Gas:  $\approx$  1 L/min Ar  
Coolant Gas:  $\approx$  14 L/min Ar

Rf-Power: 1000 – 1500 W  
Rf Frequency: 27, 40 MHz

Sample uptake:  $\approx$  1 mL/min  
Nebulizer Efficiency: 3 – 5 %



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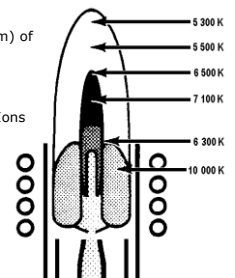
## ICP-Optical Emission Spectrometry

### Characteristics

Sample aerosol is injected in a narrow region ( $\approx$  2 mm) of very high Temperature:

- Efficient atomization
- Ionization
- Generation of electronically excited Atoms and Ions

Relaxation of excited states leads to detectable emission signals



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## ICP-Optical Emission Spectrometry



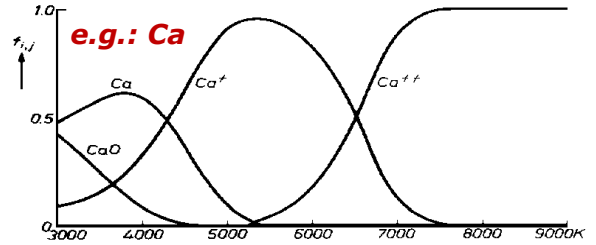
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## ICP-Optical Emission Spectrometry

### Elemental Species vs. T



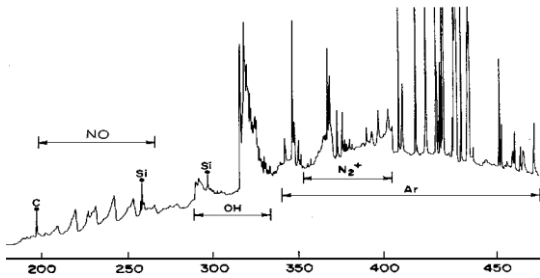
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## ICP-Optical Emission Spectrometry

### ICP Background Emission



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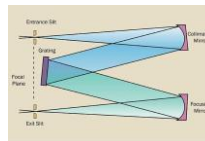


## ICP-Optical Emission Spectrometry

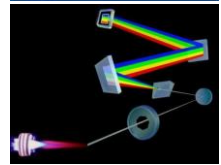
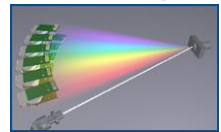
### High-resolution Optical Spectrometers required

$\Delta\lambda$ :  $\approx$  10s of pm  
Polychromators providing **simultaneous** access to the UV-VIS spectral range ( $\approx$ 130/180 – 800 nm)  
→ Paschen Runge Setup  
→ Echelle Configuration

Monochromators  
→ Czerny Turner Configuration  
(barely used in current instruments)



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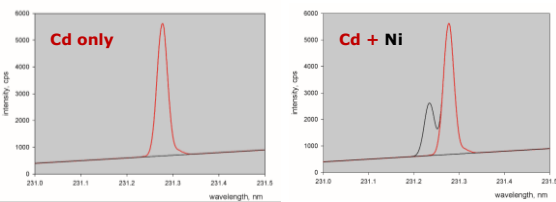


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## ICP-Optical Emission Spectrometry

### High-resolution Optical Spectrometers required



#### Identification and Correction of Spectral interferences

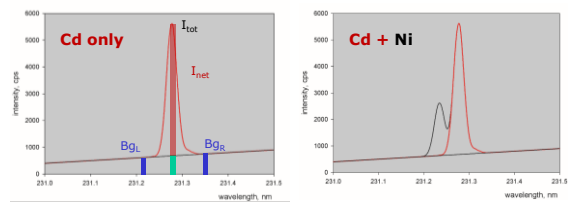
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## ICP-Optical Emission Spectrometry

### Simultaneous Spectrometers advantageous



- Correlated acquisition allows for better compensation of fluctuating baseline and interference signals.
- Internal Standard(s) can be monitored simultaneously

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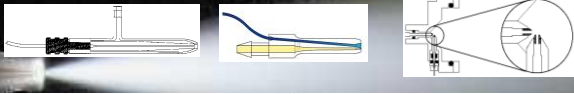
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## ICP-Optical Emission Spectrometry

### Sample Introduction Methods

Pneumatic Nebulizer  
(aerosol generation)



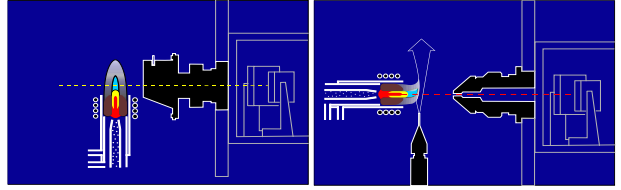
Spray Chamber  
(removal of large droplets)

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## ICP-Optical Emission Spectrometry

### Plasma View: Radial vs. Axial



Robust against Matrix  
Simpler Setup  
Lower Analyte Sensitivity

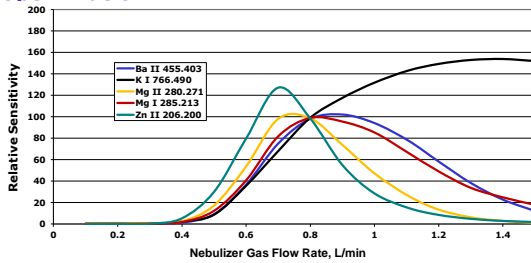
≈ 10x higher Sensitivity  
Lower Background  
Better LODs  
Stronger Matrix Dependence

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## ICP-Optical Emission Spectrometry

### Optimization



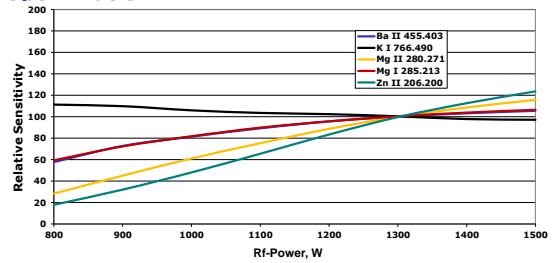
I: Atom Line, II: Ion Line

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## ICP-Optical Emission Spectrometry

### Optimization



I: Atom Line, II: Ion Line

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## ICP-Optical Emission Spectrometry

### Effects of Increasing Plasma Temperature:

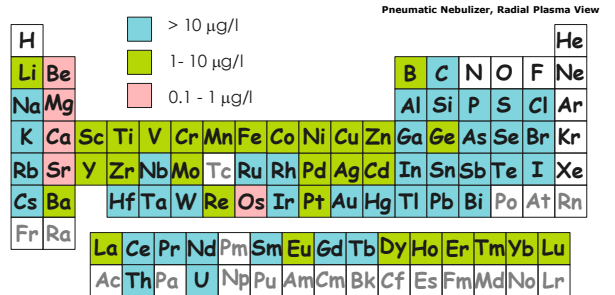
- More efficient vaporization and excitation
  - > Higher Analyte Signal
  - > Less Matrix Effects
  - > More Potential Spectral Interferences
- Increasing degree of ionization
  - > More intense Ion Lines
  - > Less intense Atom Lines
  - > More Potential Spectral Interferences
- Increasing background emission
  - > Lower Signal/Noise
- Mechanical Stress / Erosion of the Torch

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## ICP-Optical Emission Spectrometry

### Typical Limits of Detection



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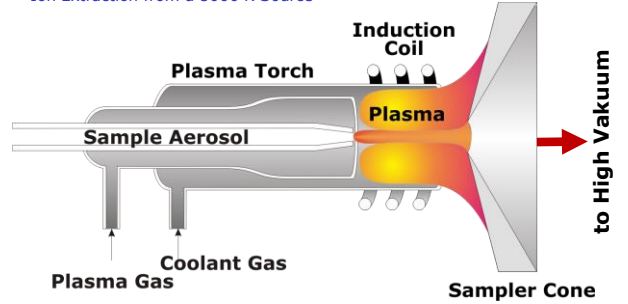
## ICP-Optical Emission Spectrometry

### Limitations:

- **Sample Composition can Influence Emission Signal**
  - More pronounced with Axial View
  - Enhancement and Suppression can occur
- **Line-rich Spectra from many Transition Elements**
  - Interference Control Mandatory
  - Background Signals may vary between Samples
- **Deposition of dissolved Solids can cause Memory Effects**
  - Long Rinse Times
  - Application-Specific Sample Introduction Systems

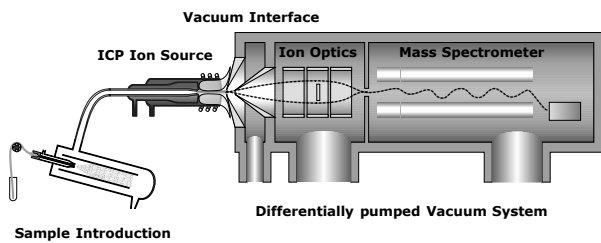
## ICP-Mass Spectrometry

Ion Extraction from a 5000 K Source



## ICP-Mass Spectrometry

### Setup



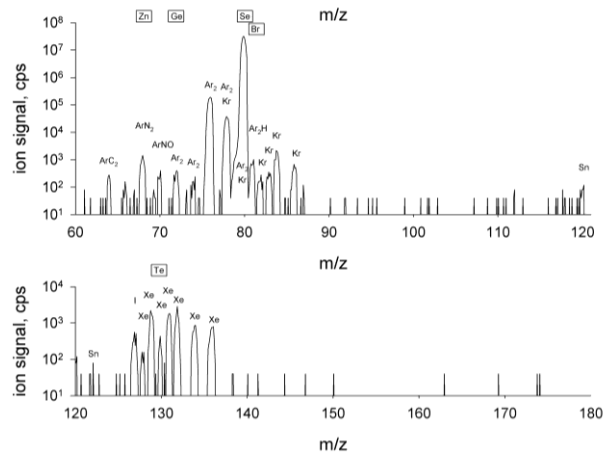
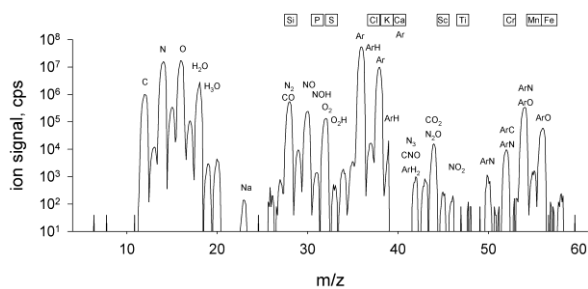
## ICP-Mass Spectrometry

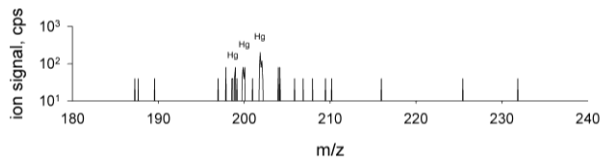
### Why ICPMS?

- Eventually lowest instrumental background
- High ion yield for most elements
  - ➔ Low Limits of Detection
- Less, and easier to predict spectral interferences
- Isotope Information
- Various Sample Introduction Methods
- Up to 12 Orders of Magnitude Linear Dynamic Range

## ICP-Mass Spectrometry

### Instrumental Background



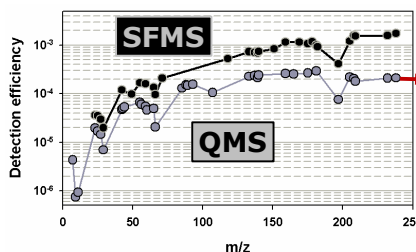


**Typical Background Contributions:**

- Plasma Gas: Ar<sup>+</sup>, Ar<sub>2</sub><sup>+</sup> Ar<sup>(2-4)+</sup> etc.
- Impurities in the Gas and ambient Air: C<sup>+</sup>, N<sup>+</sup>, O<sup>+</sup>, H<sub>2</sub>O<sup>+</sup>, Kr<sup>+</sup>, Xe<sup>+</sup>, (Hg<sup>+</sup>, Sn<sup>+</sup>, Pb<sup>+</sup>)
- Deposits in Torch, Interface: Alkaline Metals (e.g. Na<sup>+</sup>), Sample Matrix, Si<sup>+</sup>
- Molecular and Cluster Ions: C<sub>2</sub><sup>+</sup>, N<sub>2</sub><sup>+</sup>, C<sub>x</sub>O<sub>y</sub><sup>+</sup>, N<sub>x</sub>O<sub>y</sub><sup>+</sup>, Ar<sub>y</sub>H<sub>x</sub><sup>+</sup>, ArC<sub>x</sub><sup>+</sup>, ArN<sub>x</sub><sup>+</sup>, ArO<sub>x</sub><sup>+</sup>, ArN<sub>x</sub><sup>+</sup>.....

**ICP-Mass Spectrometry**

**Ion Yield**



**1 ion detected requires 20000 atoms in the source**

**ICP-Mass Spectrometry**

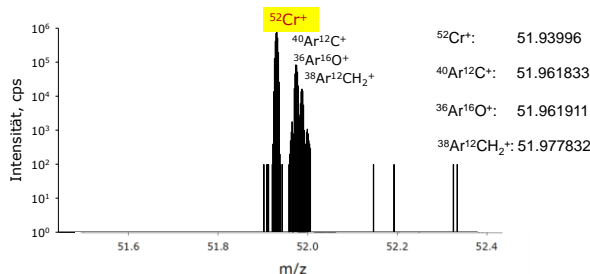
**MS Types**

- Quadrupole MS:** Ion Transmission: Moderate  
Mass Resolving Power: 0.7 m/z  
Acquisition: Sequential (0.1 ms / peak)
- Sector Field MS:** Ion Transmission: High  
Mass Resolving Power: 300 – 12000  
Acquisition: Slow Sequential (0.1 ms – 300 ms/ peak)
- Time of Flight MS:** Ion Transmission: Moderate  
Mass Resolving Power: ≈4000  
Acquisition: Simultaneous  
Measurement Speed: 0.033 ms / Spectrum

**ICP-Mass Spectrometry**

**High-Resolution Advantage**

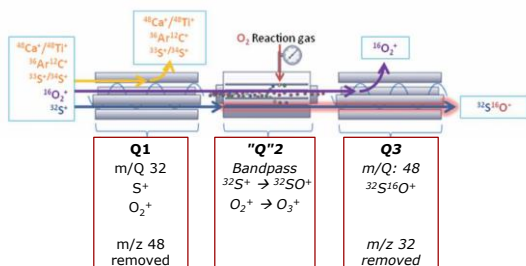
At least 5 different Species in a 1 m/z Mass Window



**ICP-Mass Spectrometry**

**"High Mass Resolution" with Quadrupole MS**

Chemical manipulation of the Ion Beam Composition:  
Ion-Molecule Reactions, MS-MS mode



**ICP-Mass Spectrometry**

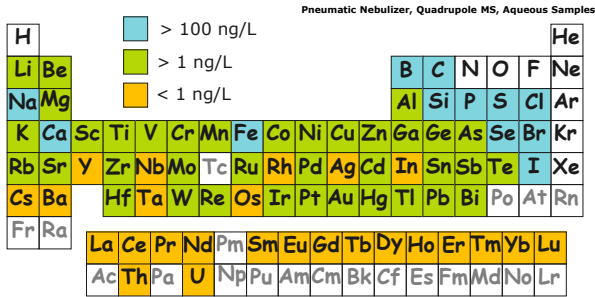
**Limitations**

**Matrix Effects are more severe:**

- **Spectral Interferences**
  - Limits the Choice of Solvents (H<sub>2</sub>SO<sub>4</sub>, H<sub>3</sub>PO<sub>4</sub> should be avoided, HCl only when absolutely needed)
- **Deposits at Vacuum Interface can cause Instrument Drift**
  - Limits the Content of dissolved Solids (1 g/L generally considered maximum)
- **«Space Charge» Effects from high Ion Currents**
- **Changes in Ion Yield:**
  - Signal Suppression (e.g. Easily Ionized Elements)
  - Signal Enhancement (e.g. changes in Space Charge)

## ICP-Mass Spectrometry

### Typical Limits of Detection



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## ICP-based Spectrometries

### Characteristics

	OES	MS
Sample Volume	mL	μL-mL
Analysis Time	seconds	seconds
Matrix Tolerance <sup>1</sup>	high (%)	low (<0.1%)
Calibration <sup>2</sup>	Ext./Std.Add.	Ext./Std.Add./ID
Repeatability <sup>3</sup>	1-5%	1-5%
Dynamic Range	10 <sup>6</sup>	10 <sup>9</sup> -10 <sup>12</sup>

1: Values in Brackets indicate the tolerable Dissolved Solids Content  
2: Ext: External Calibration, Std.Add.: Standard Addition, ID: Isotope Dilution  
3: For Concentrations > 50×LOD

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Spurenelement- und Mikroanalytik

## Calibration

### Methods

- External Calibration
  - Synthetic Solutions of the Analyte(s)
  - Matrix-Matching may be required
  - Internal Standards recommended (ICP-based methods)
- Standard Addition
  - Addition of Synthetic Solutions of the Analyte(s) to Aliquots of the Sample
  - Ideal Matrix-Matching
  - Time-consuming
- Isotope Dilution
  - Only with MS

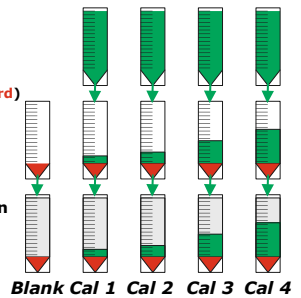
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## Calibration

### External Calibration

Known Amounts of Primary Standard(s) are filled into clean vials (eventually with an Internal Standard)  
Ideal to use different Supplies  
Dilution to desired Concentration using a suitable Solvent  
Mix!

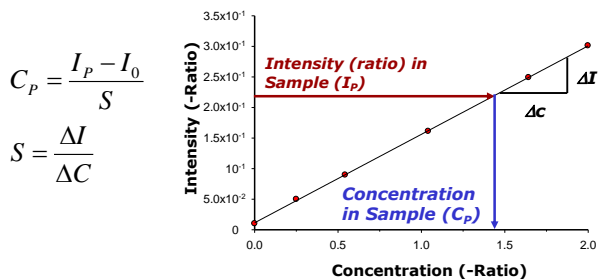


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## Calibration

### External Calibration



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## Calibration

### External Calibration

- + Simple
- + Practically all Elements accessible
- + Practically all Sample Types accessible
- + Internal Standard can be easily included
- + Concentration range only limited by Solubilities

- Spectral Interferences need to be absent or corrected for
- Matrix Effects and Instrument Drift have to be monitored and corrected for

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## Calibration

### Standard Additions

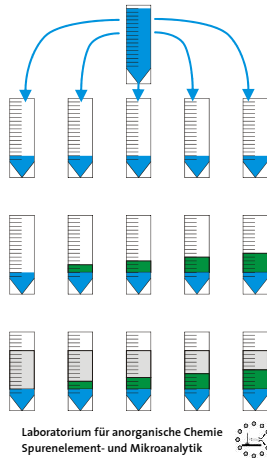
Sample splitted to identical Aliquots  
→ minimum 3, ideal 5

Addition of known amounts of a Standard Solution

Dilution to desired Concentration using a suitable Solvent

Mix!

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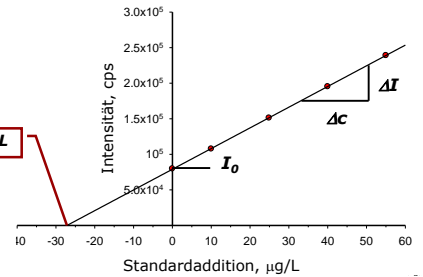
## Calibration

### Standard Additions

$$C_p = \frac{I_0}{S}$$

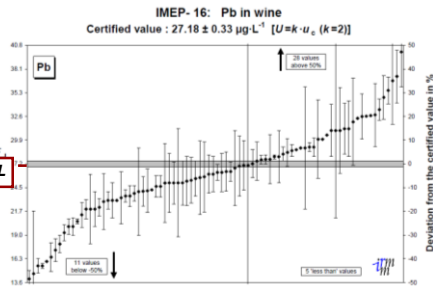
$$S = \frac{\Delta I}{\Delta C}$$

Round Robin Test  
IMEP-16, IRMM  
Pb in Wine



## Calibration

### Standard Additions



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## Calibration

### Standard Additions

+ Matrix Effects can be eliminated

- Spectral Interferences need to be absent or corrected for
- Labour intensive
- Approximate Concentration needs to be known
- Long measurement times
- Instrument Drift is not compensated for (may require another internal Standard)

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## Calibration

### Isotope Dilution (MS only)

Unknown Sample with «Natural» Isotope Ratio

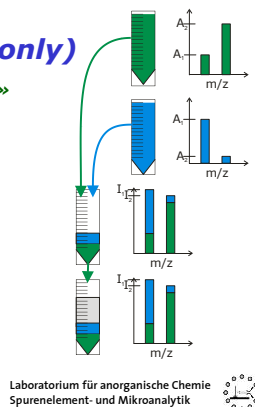
Isotopically enriched Standard

Aliquots of exactly known amount are mixed

Dilution to desired Concentration using a suitable Solvent

Mix!

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## Calibration

### Isotope Dilution (MS only)

$$R_p = \frac{A_{1P}}{A_{2P}}$$

$$R_s = \frac{A_{1S}}{A_{2S}}$$

$$R_M = \frac{I_{1M}}{I_{2M}}$$

$$C_p = C_s \times \frac{V_s}{V_p} \times \frac{R_s - R_M}{R_M - R_p} \times \frac{A_{1P}}{A_{1S}}$$

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## Calibration

### Isotope Dilution (MS only)

- + "Goldstandard" of Calibration
- + Optimum internal Standard
- + Ideal Compensation of Matrix Effects
- + SI-Traceable
- High experimental Effort
- Not Applicable with Mono-Isotopic Elements
- Spectral Interferences must be absent or corrected for
- Enriched Standards not readily available
- Instrument Drift not easily compensated for

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## Sample Preparation

### Aqueous Solutions

- Stabilization of the Elements in Solution**
  - Usually Acidification with  $\text{HNO}_3$  (Saturation of Cation-Exchange positions of the Container and Sample Introduction)
  - Specific Stabilizers may be required, depending on Chemistry
- Dilution to suitable matrix concentration**
  - Depends on Analytical Method
- Addition of Internal Standard(s)**

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## Sample Preparation

### Organic Solvents

- High variability of Viscosity, Surface Tension and Evaporation Rates causes issues with Nebulization**
  - Sample uptake Rate needs to be controlled

**Calibration Standards not readily available**

- ICP methods are less tolerant to Organic Solvents**
  - Digestion
  - Addition of trace amounts  $\text{O}_2$  to the ICP to avoid Soot formation

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## Sample Preparation

### Solids

- Conventional Methods require Digestion using a suitable Reagents**
  - Most frequently an Acid Cocktail**
    - $\text{HNO}_3$  ( $\text{HCl}$ ,  $\text{HF}$  if necessary;  $\text{H}_2\text{SO}_4$  should be avoided)
- Suitable Digestion Methods are available for most Materials**
  - Reagents and Digestion Vials need to be of sufficient Purity
- Direct Solids analysis using Laser Ablation ICPMS or Solid Sampling GFAAS**

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## Sample Preparation

### Common Digestion Methods

- Microwave assisted High Pressure, High Temperature Digestion**
  - Temperature up to 200 °C, Pressure up to 200 bar



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## Sample Preparation

### Common Digestion Methods

- Oven-heated High Temperature, High Pressure Systems**



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## Sample Preparation

### Common Digestion Methods

All Material in Contact with Sample and Reagents must be Inert and Clean

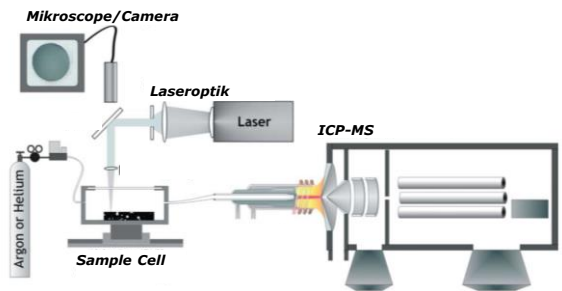
- Mostly Fluoropolymers: PTFE, PFA, etc.
- (Quartz)

Evolution of Gas (e.g. Oxidation of Organic Material) can lead to sudden Pressure Jump

- Sample loss via the Safety Relief Valve / Rupture Disk
- Potential Safety Hazard

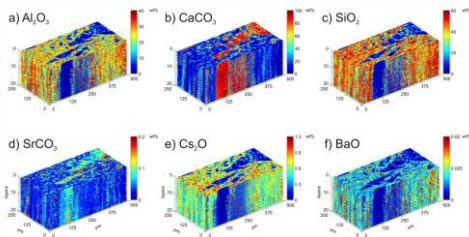
## Sample Preparation

### Direct Solid Sampling with LA



## Sample Preparation

### Direct Solid Sampling with LA



2-D and 3-D Element Distributions at 5 μm Spatial Resolution

## Method Development

### Considerations

Accuracy of the Analysis

Concentration Range

Techniques used

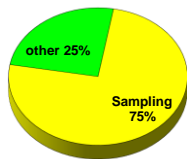
Reproducibility

Sample Throughput

Cost

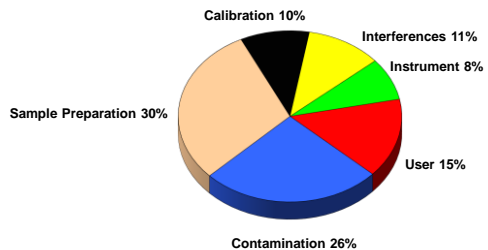
## Method Development

### Sources of Error in Trace Element Analysis



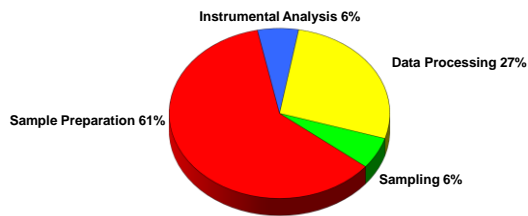
## Method Development

### Sources of Error in Trace Element Analysis



## Method Development

### Time Spent



## Method Development

### Validation

#### Ensuring Representative Analytical Results

- **Validate Representativeness of Subsamples**  
*Sampling Theory*
- **Validate Accuracy of Calibration**  
*Recovery Check Analyses*  
*Serial Dilution*  
*Matrix Evaluation*  
*Analysis of Certified Reference Materials*
- **Evaluate Reproducibility of Results**  
*Duplicate Analyses (randomized)*  
*Repeated Calibration*

